

Erik C. Smith Joins Qcept as President/COO

ATLANTA, GA. – (BUSINESS WIRE) - November 7, 2005—Qcept Technologies Inc. announced today that the company has appointed Erik C. Smith as President/COO.

Reporting to CEO Bret Bergman, Smith will be responsible for product development, applications, sales and marketing, and day-to-day operations at Qcept.

“I’m very pleased to have an executive of Erik’s caliber and accomplishments on board to assist me in leading our team. His vast experience in sales, marketing, operations, and strategic planning will be a great help at a time when the demand for our Chemical Surface Inspection™ tools is developing rapidly,” noted Qcept CEO Bret Bergman.

David Lam, Chairman of Qcept, added, “Wafer inspection is a very active segment of the semiconductor capital equipment market, and surface inspection for non-visual chemical defects is a fast-growing need. Qcept’s management is strengthened with the addition of Erik and the company is ready for its next stage of growth in this vibrant market.”

Smith’s background includes 15 years of experience in the semiconductor industry, 12 of which were with Ultratech, Inc. where his most recent position was Senior VP of World Wide Sales and Marketing. Erik led Ultratech to over 80% market share in the advanced packaging lithography business, ensured its continued dominance in the lithography market for mass production MEMS devices, and oversaw its entrée into the laser annealing equipment market. In addition, Smith’s extensive experience in Asia will increase Qcept’s market success in this high-growth region.

Remarkd Smith; “I look forward to helping Qcept grow into a market leader in Chemical Surface Inspection™ for semiconductor manufacturing. I believe our ability to rapidly detect non-visible residues on 100% of the wafer will significantly change the manner in which metrology inspection is conducted in the fab.”

About Qcept Technologies Inc.

Qcept manufactures, sells, and supports Chemical Surface Inspection™ tools to detect yield-lowering defects. Qcept’s non-destructive Chemetriq™ technology enables single atomic layer surface chemical inspection and is being adopted in fabs for full-wafer inspection of organic & metal trace contaminants undetectable by optical means.

For more information, call (404) 685-9434, email info@qceptech.com or visit www.qceptech.com.

Chemetriq is a trademark of Qcept Technologies Inc.

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